

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>	<i>Complete if Known</i>	
	Application Number	10/760,028
	Filing Date	January 16, 2004
	First Named Inventor	Jin, Been-Yih
	Group Art Unit	2891
	Examiner Name	Smith, Bradley
Sheet 1 of 7		Attorney Docket No: 42P17814

US PATENT DOCUMENTS					
Examiner Initial *	Cite No ¹	USP Document Number	Publication or Issue Date MM-DD-YYYY	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US-2002/0036290A 1	03/28/2002	Inaba, Satoshi , et al.	
		US-2002/0081794	06/27/2002	Ito, Shinya	
		US-2002/0081794A 1	06/27/2002	Ito, Shinya	
		US-2002/0167007A 1	11/14/2002	Yamazaki, Shunpei , et al.	
		US-20020074614	06/20/2002	Furuta, , et al.	
		US-2003/0057477A 1	03/27/2003	Hergenrother, John M., et al.	
		US-2003/0057486A 1	03/27/2003	Gambino, Jeffrey P., et al.	
		US-2003/0067017	04/10/2003	leong, , et al.	
		US-2003/0102497A 1	06/05/2003	Fried, David M., et al.	
		US-2003/0111686	06/19/2003	Nowak,	
		US-2003/0122186	07/03/2003	Sekigawa, , et al.	
		US-2003/0143791A 1	07/31/2003	Cheong, Kong-Soo , et al.	
		US-2003/0201458A 1	10/30/2003	Clark, William F., et al.	
		US-2003/0227036A 1	12/11/2003	Sugiyama, Naoharu , et al.	
		US-200300143791	07/31/2003	Cheong, , et al.	

EXAMINER

DATE CONSIDERED

Based on PTO/SB/08A(09-08) - Substitute Disclosure Statement Form (PTO-1449) as modified by BSTZ 03/28/07
 * EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>	<i>Complete if Known</i>	
	Application Number	10/760,028
	Filing Date	January 16, 2004
	First Named Inventor	Jin, Been-Yih
	Group Art Unit	2891
	Examiner Name	Smith, Bradley
Sheet 2 of 7	Attorney Docket No: 42P17814	

	US-20030102518	06/05/2003	Fried, , et al.	
	US-20030174534	09/18/2003	Clark, , et al.	
	US-2004/0031979A 1	02/19/2004	Lochtefeld, Anthony J., et al.	
	US-2004/0036118	02/26/2004	Adadeer et al.,	
	US-2004/0036126	02/21/2004	Chau, , et al.	
	US-2004/0036127	02/26/2004	Chau, , et al.	
	US-2004/0070020	04/15/2004	Fujiwara, , et al.	
	US-2004/0092062A 1	05/13/2004	Ahmed, Shibly S., et al.	
	US-2004/0092067A 1	05/13/2004	Hanafi, Hussein I., et al.	
	US-2004/0119100A 1	06/24/2004	Nowak, Edward J., et al.	
	US-2004/0166642	08/26/2004	Chen, Hao-Yu , et al.	
	US-2004/0180491A 1	09/16/2006	Arai, Nobutoshi, et al.	
	US-2004/0198003A 1	10/07/2004	Yeo, Yee-Chia , et al.	
	US-2004/0219722A 1	11/04/2004	Pham, Daniel T., et al.	
	US-2004/0219780	11/04/2004	Ohuchi, Masahiko	
	US-2004/0227187A 1	11/18/2004	Cheng, Zhiyuan , et al.	
	US-2004/0256647A 1	12/23/2004	Lee, Jong-Jan , et al.	

EXAMINER

DATE CONSIDERED

8/6/07

Based on PTO/SB/08A(09-06) - Substitute Disclosure Statement Form (PTO-1449) as modified by BSTZ 03/26/07
 * EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>	<i>Complete If Known</i>	
	Application Number	10/760,028
	Filing Date	January 16, 2004
	First Named Inventor	Jin, Been-Yih
	Group Art Unit	2891
	Examiner Name	Smith, Bradley
Sheet 3 of 7		Attorney Docket No: 42P17814

		US-2004/0262683A 1	12/30/2004	Bohr, Mark T., et al.	
		US-2004/0262699A 1	12/30/2004	Rios, Rafael , et al.	
		US-20040033639	02/19/2004	Chinn, , et al.	
		US-20040099966	05/27/2004	Chau, , et al.	
		US-20040108523	06/10/2004	Chen, , et al.	
		US-20040222473	11/11/2004	Risaki,	
		US-2005/0093067	05/01/2005	Yeo et al.,	
		US-2005/0093154	05/05/2005	Kottantharayil, , et al.	
		US-2005/0118790A 1	06/02/2005	Lee, Hsin-Hui , et al.	
		US-2005/0156202	07/01/2005	Rhee et al.,	
		US-2005/0184316	08/25/2005	Kim,	
		US-2005/0224800A 1	10/13/2005	Lindert, Nick, et al.	
		US-2005/0227498	10/13/2005	Furkawa,	
		US-2005/0230763	10/20/2005	Huang, , et al.	
		US-20050145944	07/07/2005	Murthy, , et al.	
		US-20050148131	07/07/2005	Brask,	
		US-20050161739	07/28/2005	Anderson, , et al.	
		US-20050170593	08/04/2005	Kang, , et al.	
		US-20050199919	09/15/2005	Liu,	

EXAMINER

DATE CONSIDERED

Based on PTO/SB/08A(09-06) - Substitute Disclosure Statement Form (PTO-1449) as modified by BSTZ 03/28/07
 * EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached

Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Complete if Known

Application Number	10/760,028
Filing Date	January 16, 2004
First Named Inventor	Jin, Been-Yih
Group Art Unit	2891
Examiner Name	Smith, Bradley

Sheet 4 of 7

Attorney Docket No: 42P17814

	US-20050215014	09/29/2005	Ahn, , et al.
	US-20050239252	10/27/2005	Ahn, , et al.
	US-20050277294	12/15/2005	Schaefer, , et al.
	US-2006/0014338	01/19/2006	Doris, , et al.
	US-20060040054	02/23/2006	Pearlstein, , et al.
	US-20060046521	03/02/2006	Vaartstra, , et al.
	US-20060202270	09/14/2006	Son, , et al.
	US-20070045748	03/01/2007	Booth, JR., , et al.
	US-4,996,574	02/26/1991	Shirasaka, , et al.
	US-5,357,119	10/18/1994	Wang, Kang L., et al.
	US-5,391,506	02/21/1995	Tada, , et al.
	US-5,521,859	05/28/1996	Ema et al.,
	US-5,543,351	08/06/1996	Yoshihiko et al.,
	US-5,739,544	04/14/1998	Koichiro et al.,
	US-5,793,088	08/11/1998	Choi, , et al.
	US-5,804,848	09/08/1998	Mukai,
	US-5,814,895	09/29/1998	Hirayama, , et al.
	US-5,821,629	10/13/1998	Wen, , et al.
	US-5,844,278	12/01/1998	Mizuno, , et al.
	US-5,899,710	05/04/1999	Mukai,
	US-6,018,176	01/25/2000	Lim,
	US-6,066,869	05/23/2000	Noble, , et al.
	US-6,150,222	11/21/2000	Gardner, Mark I., et al.
	US-6,190,975	02/20/2001	Kubo, Minoru , et al.
	US-6,259,135	07/10/2001	Hsu, , et al.
	US-6,307,235	10/23/2001	Forbes, , et al.
	US-6,359,311	03/19/2002	Colinge, , et al.
	US-6,383,882	05/07/2002	Lee, , et al.
	US-6,391,782	05/01/2002	Yu, Bin
	US-6,459,123	10/01/2002	Enders, , et al.
	US-6,472,258	10/29/2002	Adkisson, , et al.
	US-6,583,469	06/24/2003	Fried, , et al.
	US-6,630,388	10/07/2003	Sekigawa, , et al.
	US-6,642,090	11/04/2003	Fried, , et al.
	US-6,686,231	02/03/2004	Ahmed, Shibly S., et al.

EXAMINER

DATE CONSIDERED

Based on PTO/SB/08A(09-09) - Substitute Disclosure Statement Form (PTO-1449) as modified by BSTZ 03/28/07

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>	Complete if Known	
	Application Number	10/760,028
	Filing Date	January 16, 2004
	First Named Inventor	Jin, Been-Yih
	Group Art Unit	2891
	Examiner Name	Smith, Bradley
Sheet 5 of 7	Attorney Docket No: 42P17814	

	US-6,693,324	12/17/2004	Maegawa, , et al.
	US-6,716,686	04/06/2004	Buynoski et al.,
	US-6,762,469	07/13/2004	Mocuta, Anda C., et al.
	US-6,770,516	08/03/2004	Wu, , et al.
	US-6,787,402	09/07/2004	Yu,
	US-6,787,854	09/01/2004	Yang, , et al.
	US-6,798,000	09/28/2004	Luyken, , et al.
	US-6,800,885	10/01/2004	An, , et al.
	US-6,800,910	10/05/2004	Lin, , et al.
	US-6,803,631	10/12/2004	Dakshina-Murthy, , et al.
	US-6,812,075	11/02/2004	Fried, , et al.
	US-6,815,277	11/09/2004	Fried, , et al.
	US-6,821,834	11/23/2004	Ando,
	US-6,833,588	12/21/2004	Yu, , et al.
	US-6,838,322	01/01/2005	Pham, , et al.
	US-6,855,990	02/15/2005	Yeo, , et al.
	US-6,867,433	03/15/2006	Yeo, , et al.
	US-6,867,460	03/15/2005	Anderson, , et al.
	US-6869898B2	03/22/2005	Inaki, Kyoichi , et al.
	US-6,885,055	04/26/2005	Lee,
	US-6,897,527	05/24/2005	Dakshina-Murthy, , et al.
	US-6,909,151	06/21/2005	Hareland et al.,
	US-6,921,963	07/26/2005	Krivokapic, , et al.
	US-6,967,351	11/22/2005	Fried, , et al.
	US-6,974,738	12/13/2005	Hareland,
	US-7,060,539	06/13/2006	Chidambarrao, , et al.
	US-7,105,390	09/12/2006	Brask, , et al.
	US-7,105,894	09/12/2006	Yeo et al.,
	US-7,154,118	12/26/2006	Lindert,

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code/Number/Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ²
		DE-10203998	08/21/2003	Infineon Technologies,		
		EP-0623963A1	11/09/1994	Siemens Aktiengesellschaft,		
		EP-1091413	04/11/2001	LSI Logic Corp,		
		GB-2156149	03/14/1984	Nicholas,		
		JP-06005856	01/14/1994	Kawasaki Steel Corp,		
		JP-2001338987	12/07/2001	Seiya,		
		JP-2002-298051	10/11/2002	Takefuchi, Hiroshi		
		JP-2303048	12/17/1990	Nissan Motor,		

EXAMINER

DATE CONSIDERED

Based on PTO/SB/08A(09-06) - Substitute Disclosure Statement Form (PTO-1449) as modified by BSTZ 03/26/07
 * EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>	<i>Complete if Known</i>	
	Application Number	10/760,028
	Filing Date	January 16, 2004
	First Named Inventor	Jin, Been-Yih
	Group Art Unit	2891
	Examiner Name	Smith, Bradley
Sheet 6 of 7		Attorney Docket No: 42P17814

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code/Number/Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ²
		JP-59145538	08/21/1984	Youichi, Tamaoki, et al.		
		WO-03003442	01/09/2003	Infineon Technologies,		
		WO-2005036651	04/21/2005	NEC Corp,		

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS						
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				T ²
		"International Preliminary Report On Patentability", <u>PCT/US2005/010505</u> , October 12, 2006, (10/12/2006), 16 pgs				
		"International Search Report & Written Opinion", <u>PCT/US2004/032442</u> , June 16, 2005, 12 pgs				
		"International Search Report & Written Opinion", <u>PCT/US2006/025751</u> , Filed June 12, 2006, 1-14				
		"International Search Report & Written Opinion", <u>PCT/US2006/024516</u> , January 17, 2007, 18				
		"International Search Report & Written Opinion", <u>PCT/US2006/037634</u> , (May 31, 2007), 21 pgs				
		BUCHANAN, D. A., et al., "Fabrication of Midgap Metal Gates Compatible With Ultrathin Dielectrics", <u>Applied Physics Letters</u> 73.12, (9/21/1998), pgs. 1676-1678				
		CHANG, L., et al., "CMOS Circuit Performance Enhancement by Surface Orientation Optimization", <u>IEEE Transactions on Electron Devices</u> , Vol. 51, No. 10, (10/2004), pp 1621-1627				
		CLAFLIN, B., et al., "Interface Studies of Tungsten Nitride And Titanium Nitride Composite Metal Gate Electrodes With Thin Dielectric Layers", <u>Journal of Vacuum Science and Technology A</u> 16.3, (May/June 1998), pgs. 1757-1761				
		HWANG, JEONG-MO, et al., "Novel Polysilicon/Tin Stacked-Gate Structure for Fully-Depleted SOI/CMOS", <u>International Electronic Devices Meeting Technical Digest</u> , (1992), pgs. 345-348				
		IEONG, et al., "Three Dimensional CMOS Devices and Integrated Circuits", <u>IEEE CICC</u> , San Jose, CA September 21-24, (2003), 207-217				
		JONES, E. C., et al., "Doping Challenges in Exploratory Devices for High Performance Logic", 14th Int'l Conference, Piscataway, NJ, September 22-27, (2002), 1-6				
		LUDWIG, et al., "FinFET Technology for Future Microprocessors", 2003 IEEE Int'l. SOI Conference, New Port Beach, CA, September 29 - October 2, (2003), 33-34				
		NACKAERTS, et al., "A 0.314um ² 6T-SRAM Cell build with Tall Triple-Gate Devices for 45nm node applications using 0.75NA 193nm lithography", <u>IDEM 2004</u> , 269-272				
		NOWAK, E. J., et al., "A Functional FinFET-DGCMOS SRAM Cell", Int'l. Electron Devices Meeting, San Francisco, CA December 8-11, (2002), 411-414				

EXAMINER

DATE CONSIDERED

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>	<i>Complete If Known</i>	
	Application Number	10/760,028
	Filing Date	January 16, 2004
	First Named Inventor	Jin, Been-Yih
	Group Art Unit	2891
	Examiner Name	Smith, Bradley
Sheet 7 of 7		Attorney Docket No: 42P17814

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		NOWAK, E. J., et al., "Scaling Beyond the 65 nm Node with FinFET-DGCMOS", IEEE CICC, San Jose, CA September 21-24, (2003), 339-342	
		NOWAK, EDWARD J., et al., "Turning Silicon On Its Edge.", IEEE Circuits & Devices Magazine Vol 1, (Jan/Feb 2004),	
		PARK, DONGGUN, et al., "3-dimensional nano-CMOS Transistors to Overcome Scaling Limits", IEEE 2004, ISBN 0-7803-8511-X, 35-40	
		PARK, et al., "PMOS Body-Tied FinFET (Omega MOSFET) Characteristics", Device Research Conference, Piscataway, NJ, June 23-25, IEEE, June 2003, 33-34	
		PARK, JAE-HYOUN, et al., "Quantum-Wired MOSFET Photodetector Fabricated by Conventional Photolithography on SOI Substrate", Nanotechnology, 2004, 4th IEEE Conference on Munich, Germany, August 16-19, 2004, Piscataway, NJ, pgs 425-427, XP010767302	
		SEEVINCK, EVERT, et al., "Static Noise Margin Analysis of MOS SRAM Cells", IEEE, Journal of Solid-State Circuits, (SC-22)5, (1987), 1-7	
		STADELE, M., et al., "A Comprehensive Study of Corner Effects in Tri-gate Transistors", IEEE 2004, Pgs 165-168	
		STOLK, PETER A., et al., "Modeling Statistical Dopant Fluctuations in MOS Transistors", IEEE Transactions on Electron Devices, (45)9, (1998), 1960-1971	
		SUGIZAKI, T., et al., "Novel Multi-bit SONOS Type Flash Memory Using a High-k Charge Trapping Layer", VLSI Technology, 2003. Digest of Technical Papers. 2003 Symposium on 10-12 June 2003., pgs. 27-28	
		YANG-KYU, CHOI, et al., "Sub-20nm CMOS FinFET Technologies", IEEE, IEDM 01-421 to 1-424, (2001), 1-4	

EXAMINER

DATE CONSIDERED

Based on PTO/SB/08A(09-06) - Substitute Disclosure Statement Form (PTO-1449) as modified by BSTZ 03/28/07
 * EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached